The Transmission Electron Microscope

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Outline

Why Electrons?

Types of interactions

The TEM

Vacuum system

Electron source

Lenses

Condensor system

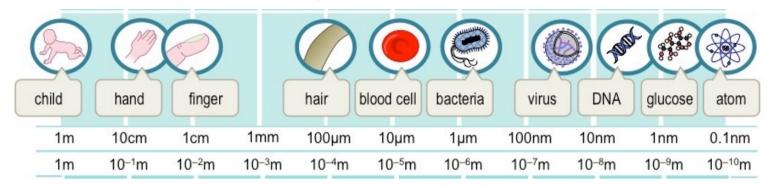
Objective Lens

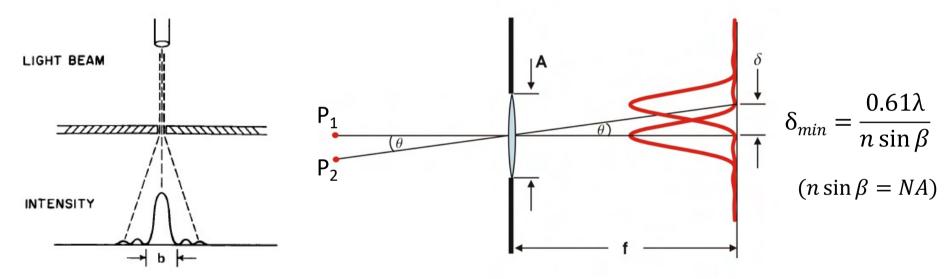
Imaging system

Aberrations and correctors

Suggested Reading

Why Electrons?





Limiting aperture → diffraction Point source → airy disk (b) Rayleigh's criterion: to resolve two point sources, P1 airy disk maxima overlays first minima of P2.

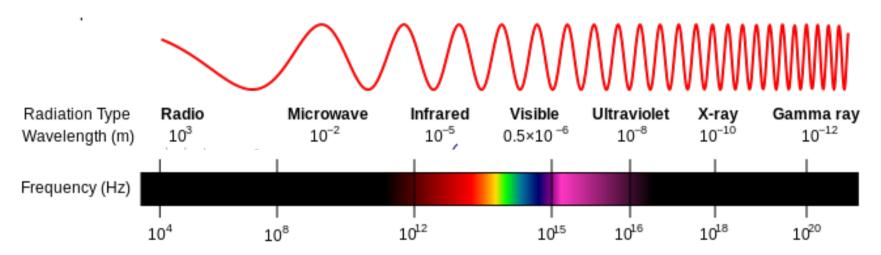
Resolution dependent on wavelength and numerical aperture (NA)

In EM, NA tends to unity



To image 1Å, $\lambda = 0.5\text{Å}$

Why Electrons?



$$\lambda = \frac{h}{p} = \frac{h}{m_e v}$$

Electrons act as both particles and waves

Debroglie equation

The wavelength of electrons depends on velocity

We can control wavelength of electrons by voltage

To match x-rays we need a voltage between 1-1000kV

Higher voltage = shorter wavelength.

But higher energy = more specimen damage

Biological TEM operate at 300kV max: λ ~0.2pm

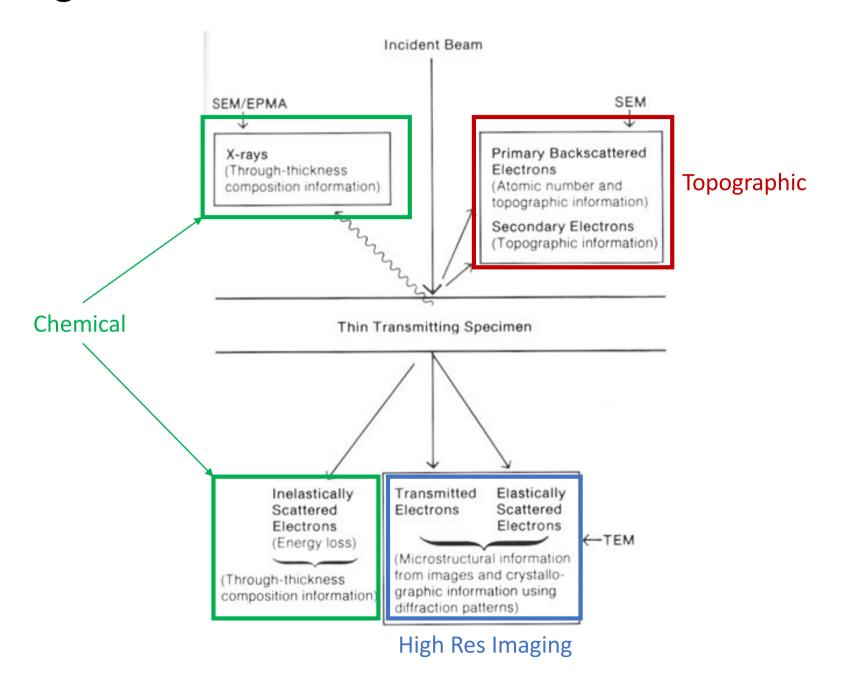
$$\lambda(nm) \approx \sqrt{\frac{1.5}{V}}$$

Current max resolution

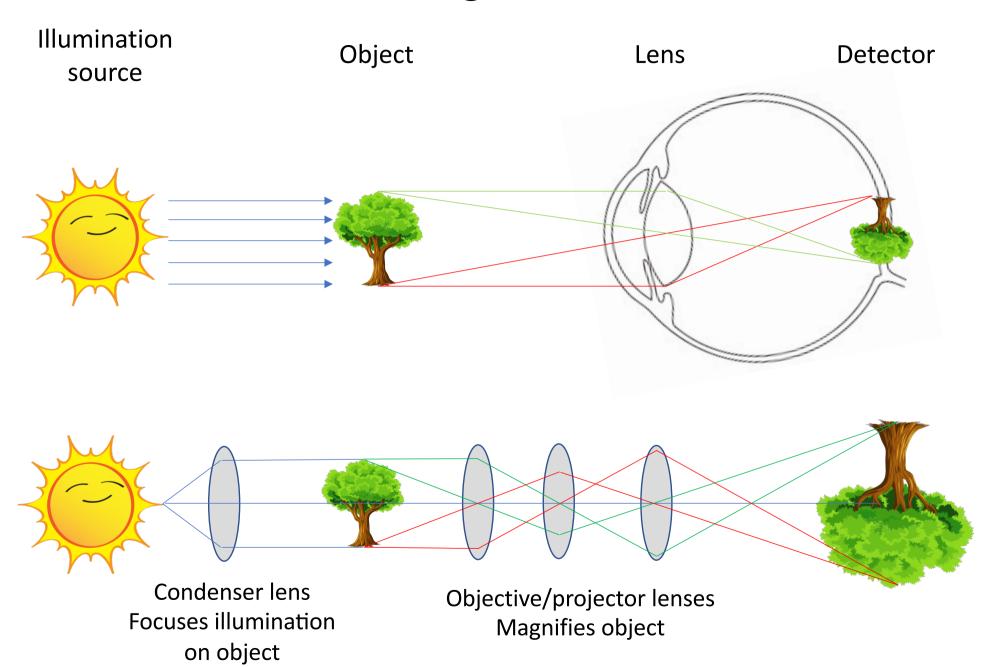
Materials: 0.05 nm

Biology: 0.14 nm

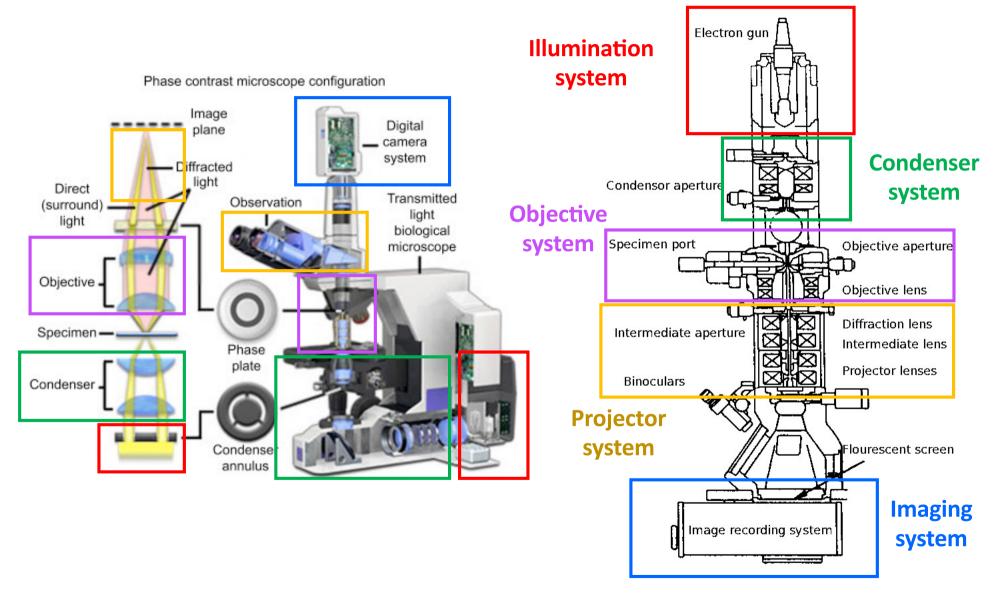
Signals from Electron Interaction with Matter



Basic Image Formation

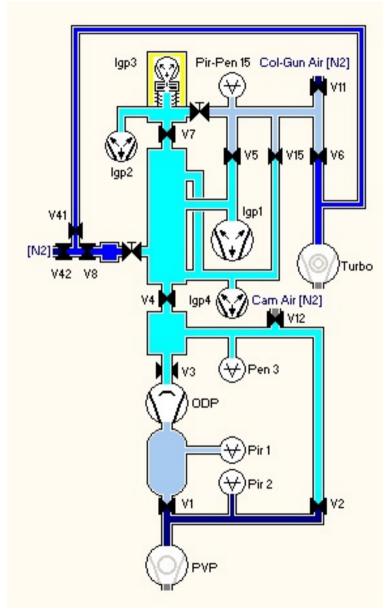


Light vs. Electron Microscope

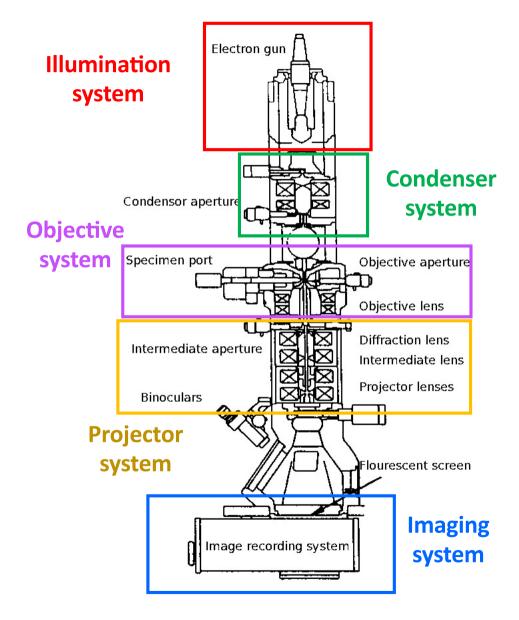


Light

Light vs. Electron Microscope

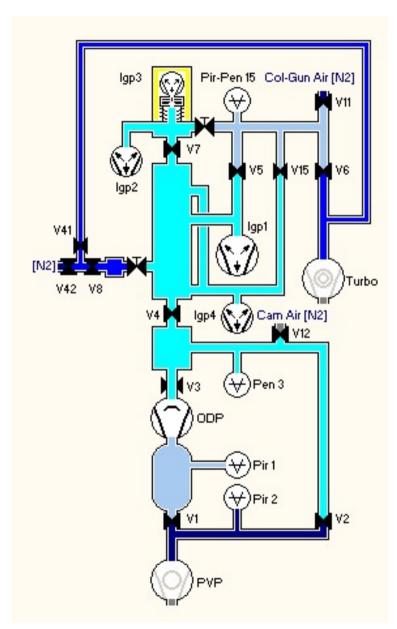






Electron

Vacuum System



Vacuum system

Why operate in vacuum?

Electrons interact well with matter

Mean-free-path length: 20 cm in air

2 km in vacuum

How is vacuum achieved?

Rotary pump — ATM to rough vac.

• Oil diffusion pump (ODP) / Scroll Pump - low vac

Turbo pump — high vacuum

lon getter pump (IGP) – ultra high vacuum

Cryo-pump/trap — high vacuum

How is vacuum monitored?

Pirani gauge (Pir) — ATM to low vac

Penning gauge (Pen) — high vac

Current readout (IGP) — ultra high vac

 $1Pa = 0.01 \, mbar$

Room Pressure: 10⁵ Pa

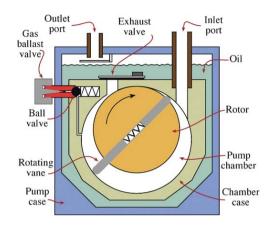
Rough Vacuum: 100-0.1 Pa

Low Vacuum: $0.1 - 10^{-4}$

High Vacuum: $10^{-4} - 10^{-7}$ Pa

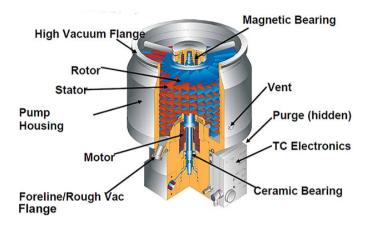
Ultra High Vacuum: 10^{-7} Pa and below

Vacuum System



Pocket of Trapped Gas

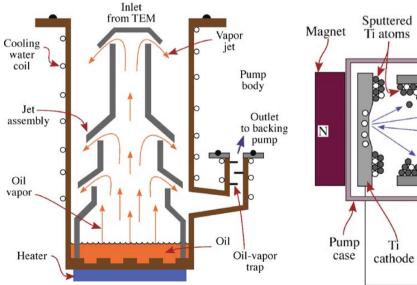
Orbiting Scroll



Rotary pump

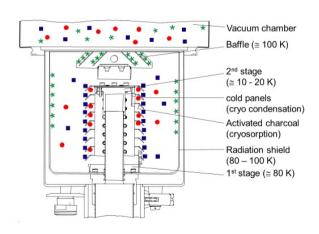
Scroll Pump

Turbo Pump



Magnet Ti atoms Inlet from TEM

Ti atoms



Oil Diffusion Pump

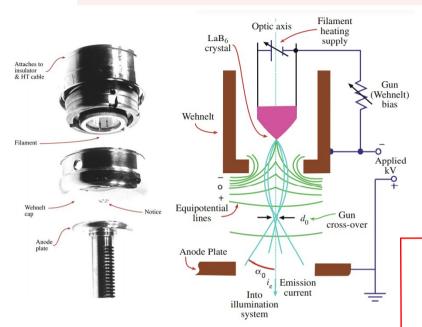
Ion Getter Pump

Cryo-pump

Electron Source

Thermionic

Field Emission



FE tip

V₁

V₀

First anode

Second anode

Gun quality:

Temporal coherence – Wavelength spread Spatial coherence – Angular spread

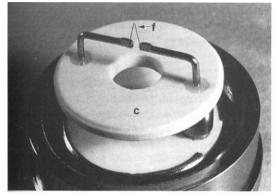
	Units	Tungsten	LaB ₆	Schottky FEG	Cold FEG
Work function, Φ	eV	4.5	2.4	3.0	4.5
Richardson's constant	A/m ² K ²	6×10^{9}	4×10^9		
Operating temperature	K	2700	1700	1700	300
Current density (at 100 kV)	A/m ²	5	10 ²	10 ⁵	10 ⁶
Crossover size	nm	> 10 ⁵	10 ⁴	15	3
Brightness (at 100 kV)	A/m ² sr	10 ¹⁰	5 × 10 ¹¹	5 × 10 ¹²	10 ¹³
Energy spread (at 100 kV)	eV	3	1.5	0.7	0.3
Emission current stability	%/hr	<1	<1	<1	5
Vacuum	Pa	10^{-2}	10^{-4}	10^{-6}	10^{-9}
Lifetime	hr	100	1000	>5000	>5000
Cost of tip		£80	£800	£8000	£8000
Time to replace		1-2 days	1-2 days	5-8 days	5-8 days

Filaments

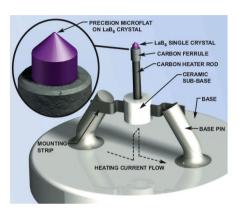
Tungsten (W)

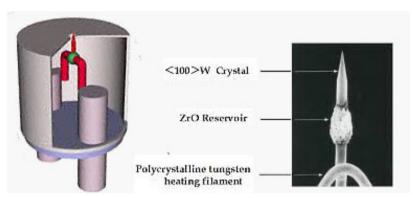
LaB₆

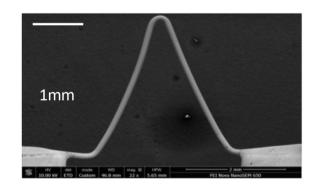
FEG (W)

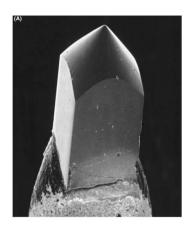


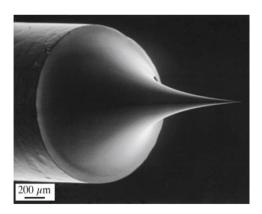
Bozzola and Russell, Fig. 6.22



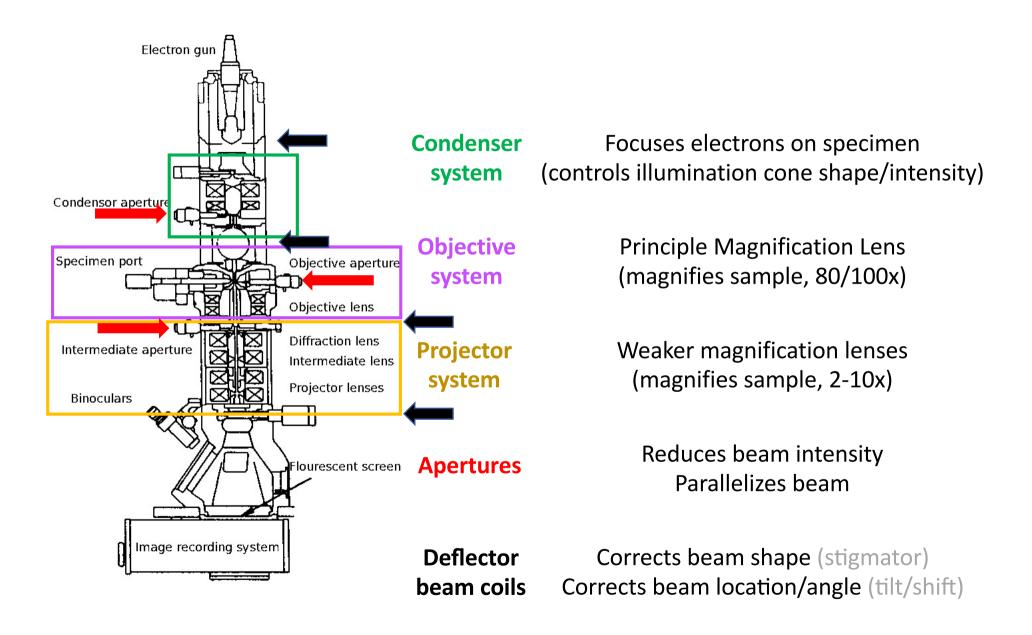




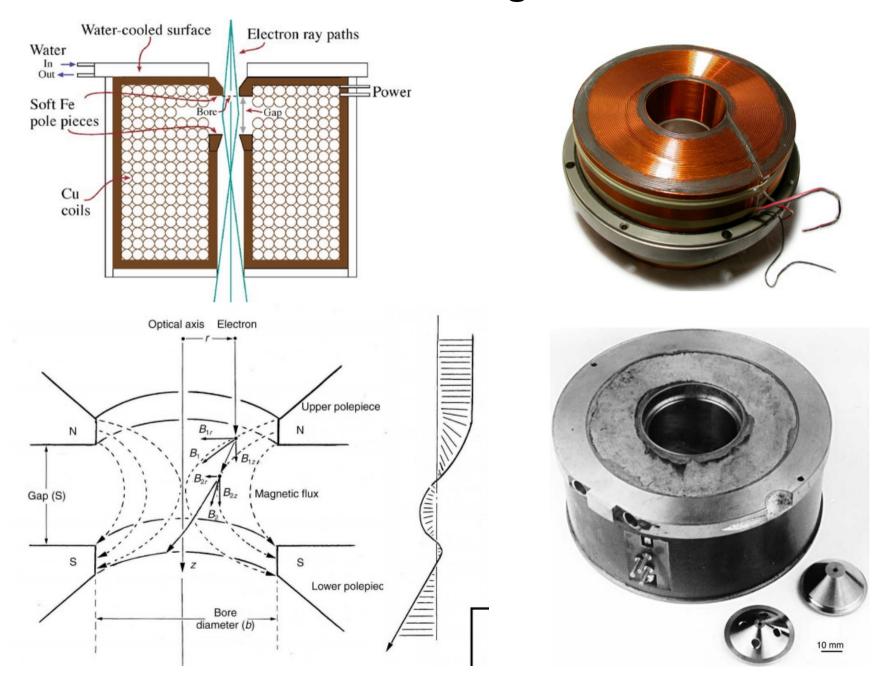




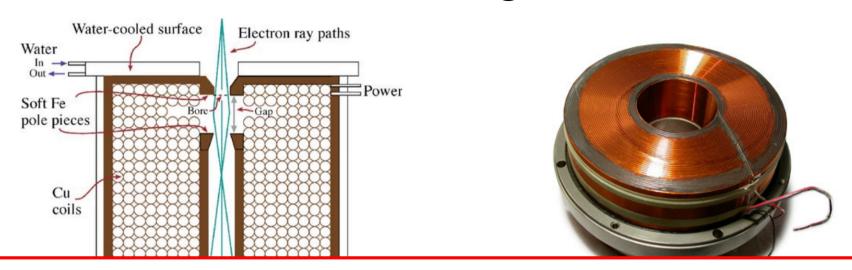
The Lens System



The Condensing Lens



The Condensing Lens



Magnetic lenses are poor quality and have severe aberrations (aberrations increase with distance from centre)

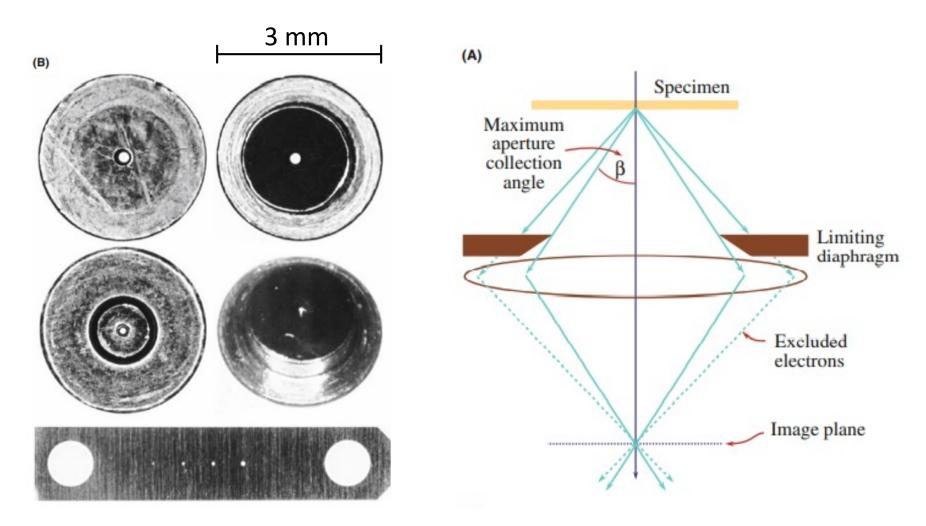
"a magnetic lens is like using the bottom of a soda bottle as a magnifying glass"

"if our eye lens worked as well as a magnetic lens we would be *legally blind*"

(quotes in William and Carter)



Apertures



Condenser aperture
Objective aperture
Selective area aperture

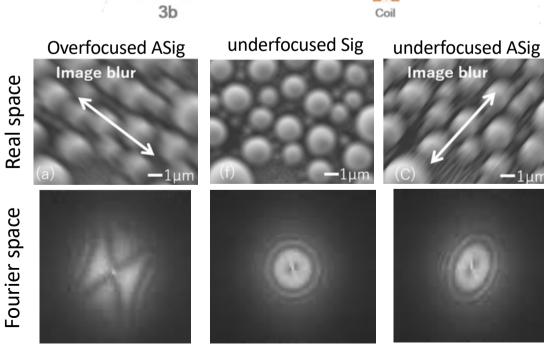
Controls beam intensity, parallelity Amplitude contrast Diffraction imaging/dark field

Deflector Coils

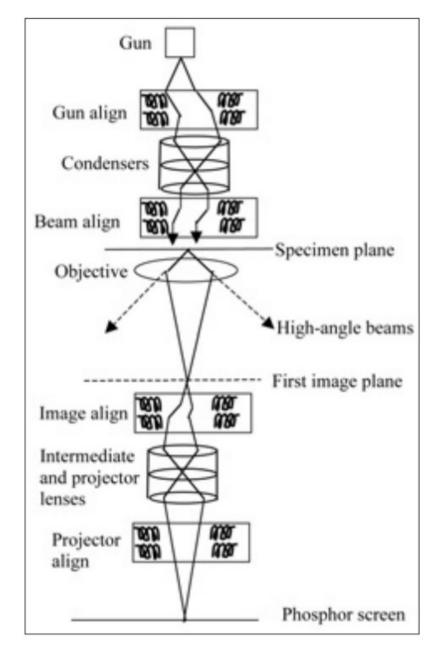


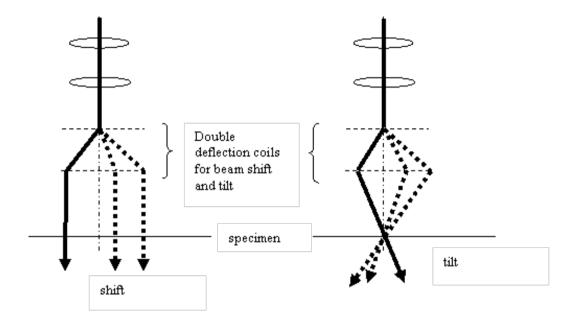
Condenser stigmators correct beam shape (circle vs. oval)

Objective stigmators correct image



Shift/Tilt Coils





- 1. Get the beam down the scope
- 2. Make sure beam is parallel/aligned to optical axis (bright field imaging)
- 3. Low dose imaging
- 4. Automatic procedures (e.g. eucentric height/focus)

Condensor System

Gun tilt/shift: sets up beam to enter condenser system on optical axis

C1 = Spot size, controls beam size and quality

Spot 9: Strongest lens setting

Highest crossover

Dimmest beam and smallest focused beam

Most coherent little spatial divergence

Only most parallel electrons reach specimen

Spot 1: Weakest lens setting

Lowest crossover

Brightest & largest focus beam diameter

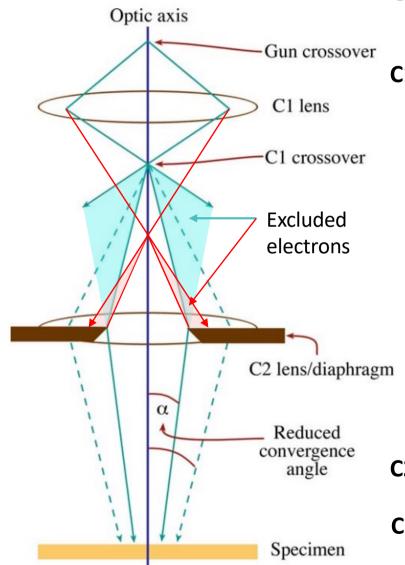
Least coherent

Greatest spatial divergence

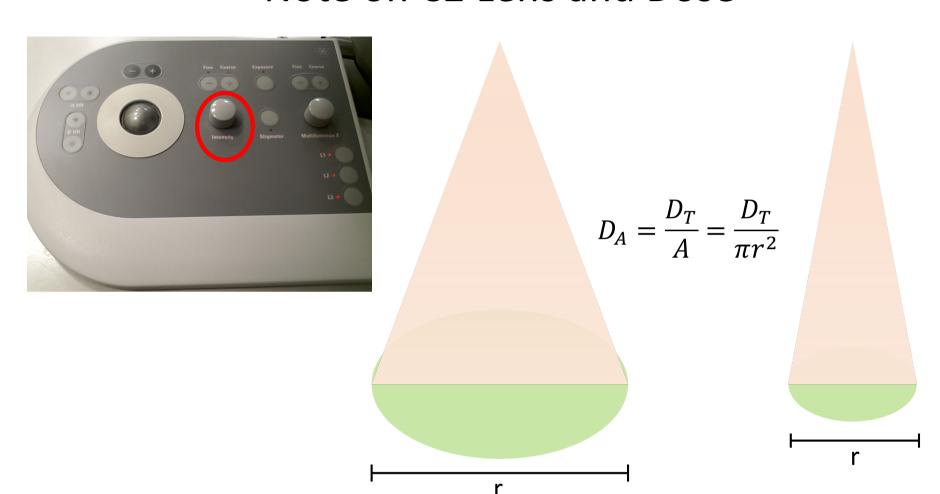
Majority of electrons reach specimen

C2 aperture = limits amount of electrons reaching sample

C2 lens = Intensity knob. Controls diameter of beam reaching sample → (Dose/beam intensity)



Note on C2 Lens and Dose



Dose in an area increase 4x when you half the radius.

USE THIS INTENSITY CONTROL KNOB WISELY!

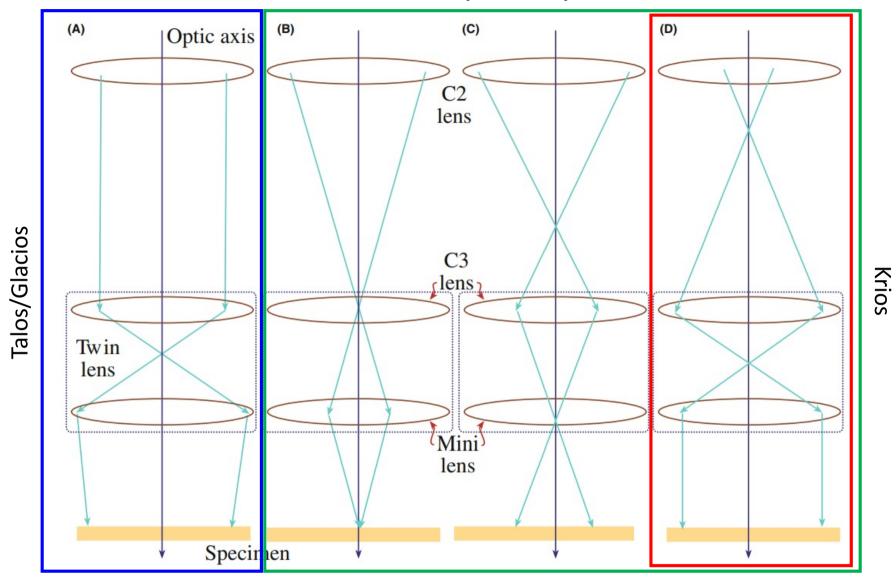
DA = Dose per unit area

DT = Total dose In beam

A = Area

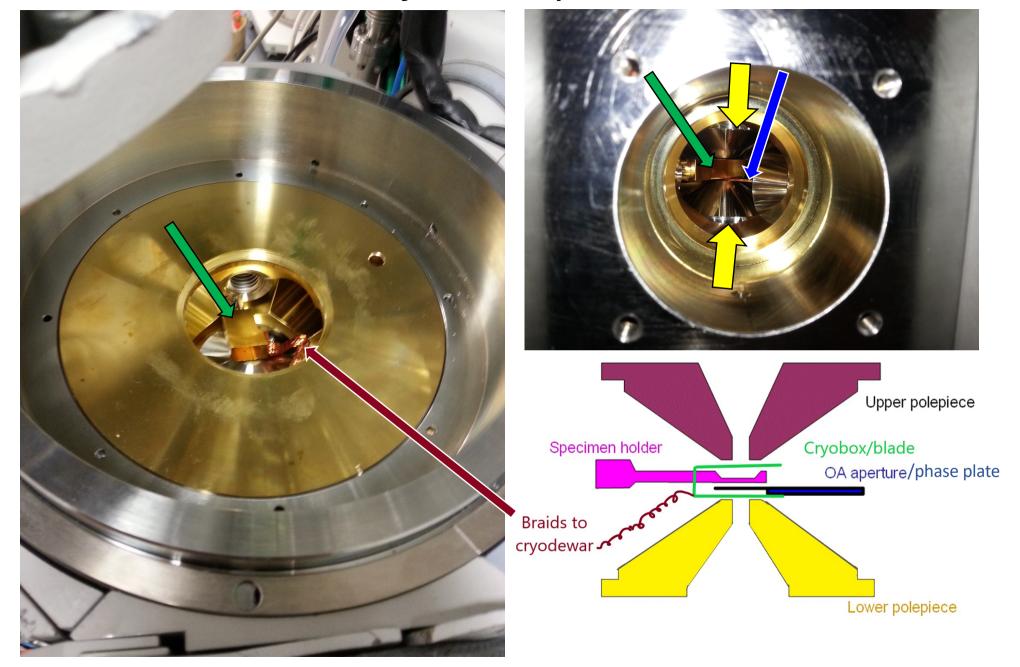
r = Beam Radius

C3 Lens (Krios)

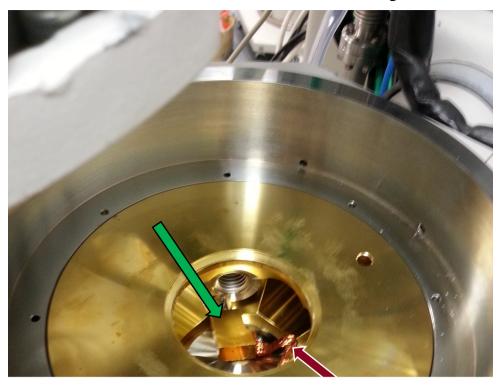


Parallel illumination of specimen reduces aberrations C3 lens provides parallel illumination but only at certain C2 values

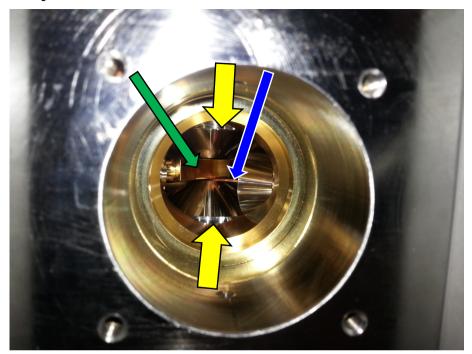
Objective System

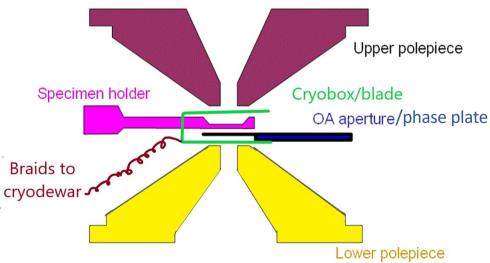


Objective System



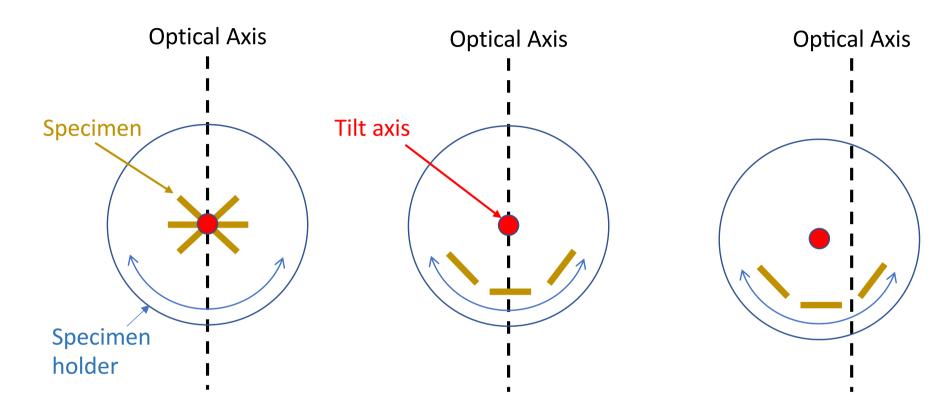
- Cryoblades cooled to LN₂ temp by braids
- Cryoblades colder than sample → cryotrap
- Keeps sample clean and cold by absorbing contaminant from sample/column
- Cryoblades needs to be warmed up regularly to remove contaminants → cryocycle
- Cryocycle: turns off IGP, pumps specimen chamber with Turbo





Gap between pole pieces is spherical aberration (Cs). Smaller gap = better.

Eucentric Height



Excellent!

Tilt axis aligns on optical axis and eucentric focus

Specimen does not move when tilted

Bad

Specimen moves when tilted

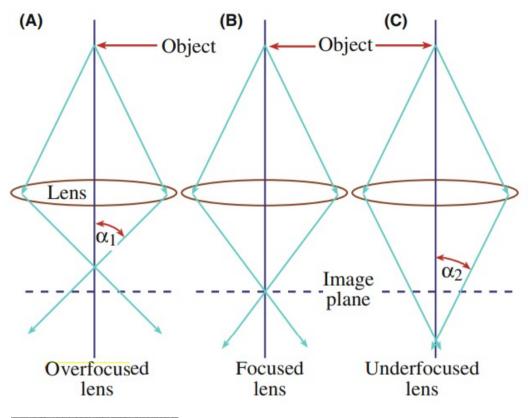
Change specimen Z-height

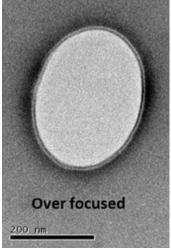
Very Bad

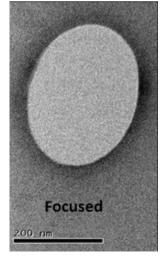
Specimen moves when tilted

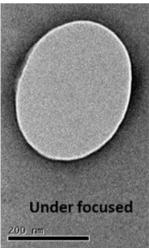
Change specimen Z-height Software or engineer required to align tilt axis with optical axis

Focus











Focus knob modulates objective lens current changes clarity of image (focus)

If crossover above image plane - overfocused

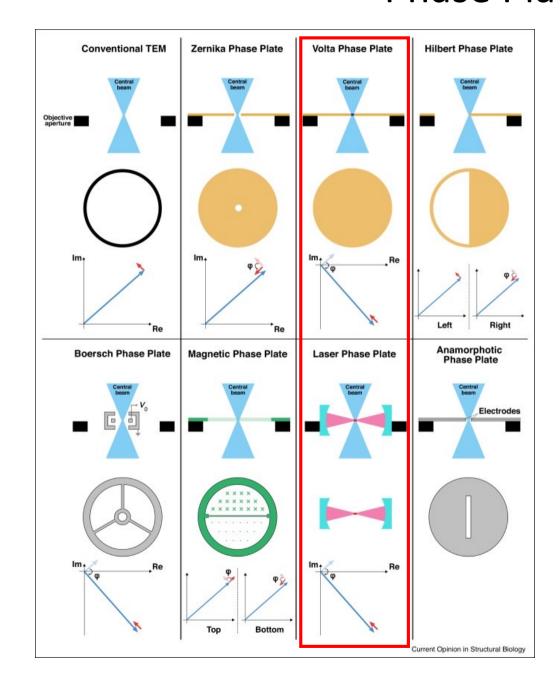
If crossover below image plane - underfocused

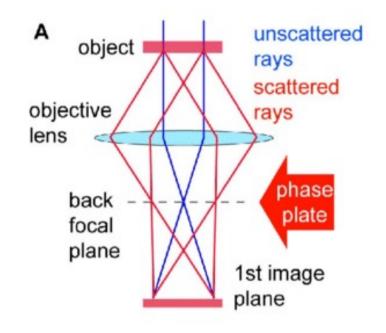
Biological samples contain light atoms so minimal phase shifts occurs between scattered and unscattered rays

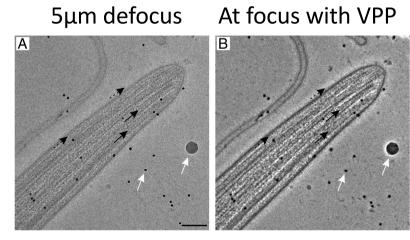
→ At focus, very little contrast

To see sample, either image underfocus or use phase plate

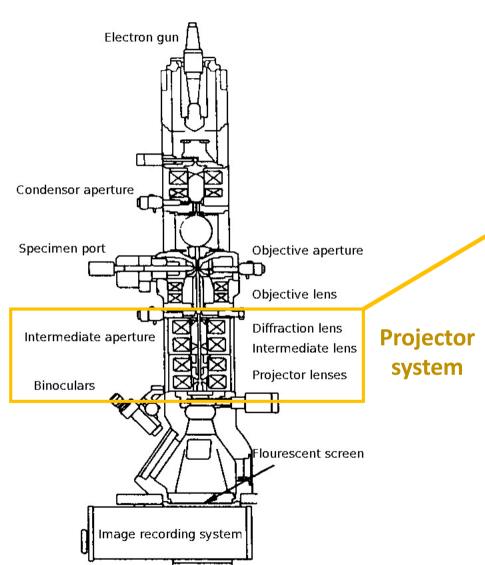
Phase Plates







Projector System





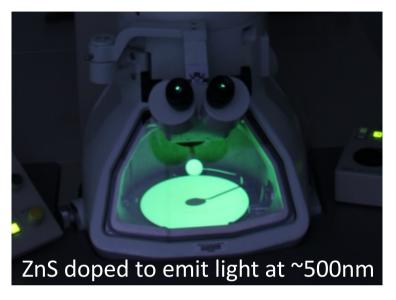
Responsible for magnification in SA mode (record mode)

Magnification knob changes strength of projector lens

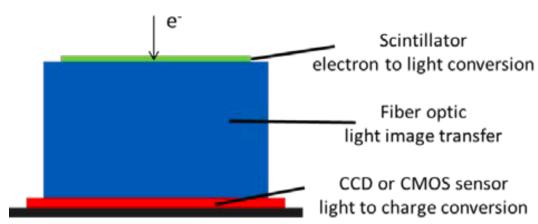
Objective stays constant (prevents hysteresis)

Imaging System

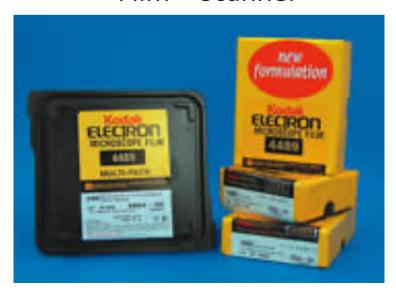
Fluorescent Screen



Charge coupled device (CCD)

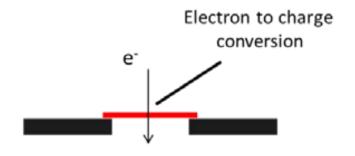


Film + Scanner



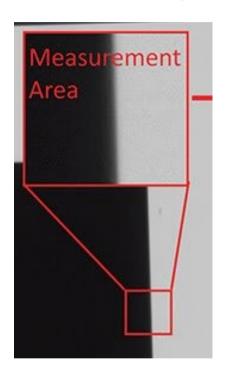
Direct Electron Detectors (DEDs)

(e.g. K3/Falcon)



Camera Quality Measurement

Modular transfer function (MTF)



How fast does intensity change at sharp edge?

Fast change, great camera, able to capture high resolution data

Slow change, poor camera, resolution limiting

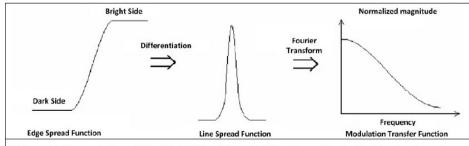
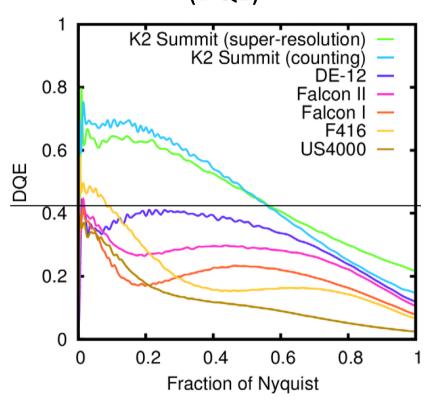


Figure 3. Computation of the Modulation Transfer Function using the knife-edge target.

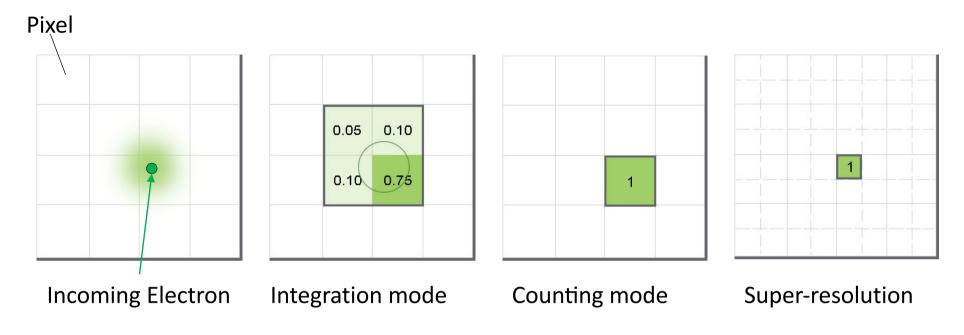
Detection Quantum Efficiency (DQE)



$$DQE = \frac{SN_{out}^2}{SN_{in}^2}$$

DQE = 1, excellent camera, no loss of signal Greater the Fraction of Nyquist, > resolution

Integrated vs Counted (super-resolution) Mode



Electron hits pixel array and causes charge spread

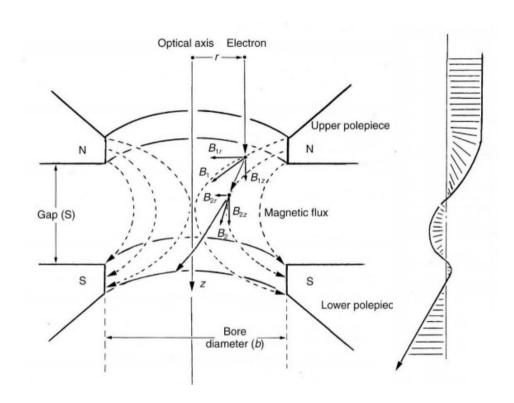
Integrating mode reads out accumulated charge in each pixel

Assumes 1e⁻ in, 1e⁻ out. Calculates most probably location of electron hit.

Subdivides pixel to give more accurate location of electron hit.

Nyqyist: maximum resolution of detector (2*px size) represented by sine wave where 1px white, next black (smallest sampling frequency)

Lens Aberrations



Lenses imperfect

Deflect beam differently depending on:

Entrance location Angle of entry Wavelength

Aberration greatest furthest from optical axis.

Spherical Aberration

- Entry of electron to lens

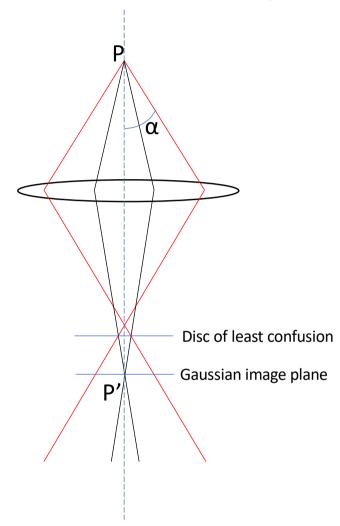
Chromatic Aberration

- Wavelength of Electron

Coma

Angle of entry

Spherical Aberration (Cs)



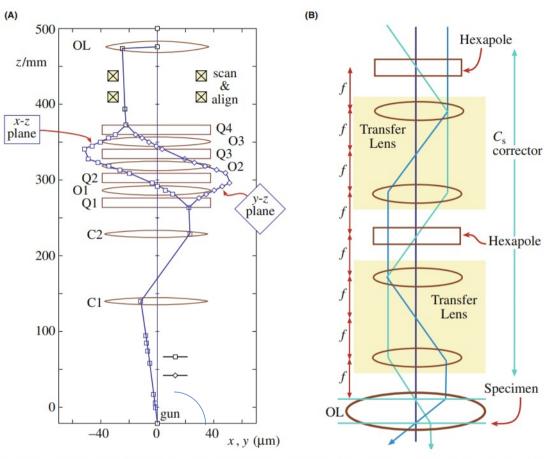
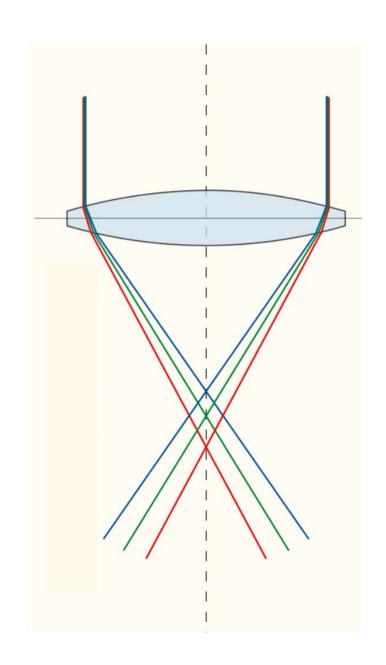


FIGURE 6.12. Ray diagrams showing how the two different commercial systems use (A) multiple quadrupole (Q) and octupole (O) lenses (Nion) or (B) hexapole and other transfer lenses (CEOS) to correct for C_s.

- Lenses are strongest at edge
- Thus off-axis electrons bent more than on-axis
- Different focus points

Cs correctors available on some scopes Important if imaging at 0.5Å resolution

Chromatic Aberration (Cc)



Electrons of different wavelengths are focused at different point

Cause of wavelength variation:

Electron source

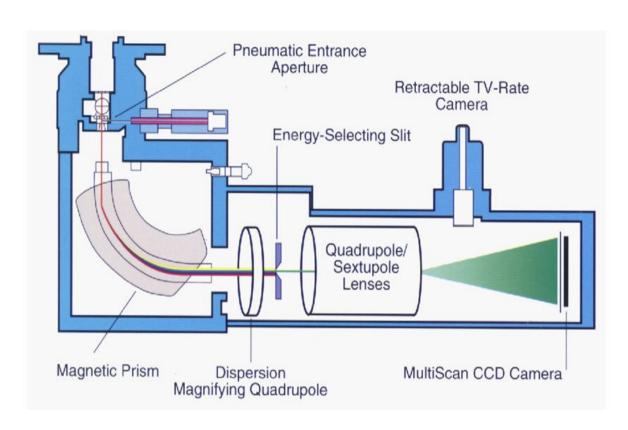
Interaction with sample

(especially thick samples)

Correct using:

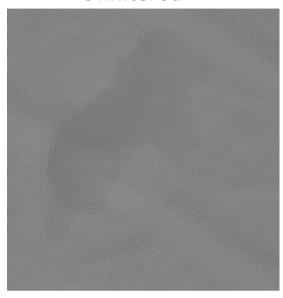
CFEG instead of Tungsten
Monochromator after gun
Energy filter after sample imaging

Energy Filter

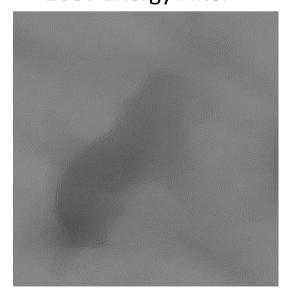


- Elaborate mass spec
- Select for specific wavelength
- Zero-loss imaging (elastically scattered waves)
- EELS Selects wavelength of inelastically scattered rays – chemical composition



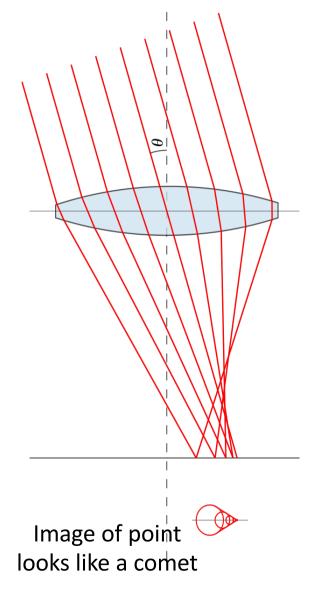


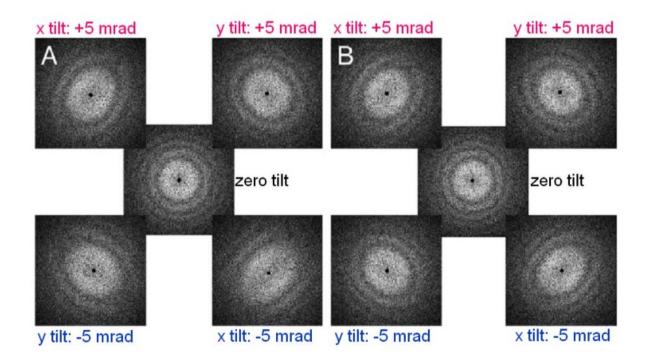
20eV Energy Filter



Coma

- Beam enters lens at angle
- Cs causes rays to bend depending on location
- Point source becomes comet shaped
- To correct: Apply +/- beam tilt
- FFT of opposite beam tilts should be identical





Suggested Reading

David B. Williams • C. Barry Carter **Transmission Electron** Microscopy A Textbook for Materials Science **Second Edition**

http://myscope.training/#/TEMlevel_2_4

Flash of TEM:

http://www.doitpoms.ac.uk/tlplib/tem/illumination.php

http://cryo-em-course.caltech.edu/overview

Youtube